IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership	Pub	Stan	
* 5 5		Xplore RELEASE 1.8	

dards Conferences Careers/Jobs



Help FAQ Terms IEEE Peer Review Quick Links Welcome to IEEE Xplore What Can I Access the IEEE Member Digital Library Prior C. Access the IEEE Enterprise File Cabinet A Can IEEE Xplore Quick Links You resert matched 17 of 1121826 documents. A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order. Refine This Search: You may refine your search by editing the current search expression or entering new one in the text box. [edge or contour or line or ridge) <page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)<page: paragraph="">(((inter) Search) [cdge or contour or line or ridge)Search [cdge or contour or line or ridge) [cdge o</page:></page:></page:></page:></page:></page:></page:>		Welcome United States Patent and Trademark Office
O Home O What Can I Access? O Log-out Tables of Contents O Journals & Magazines O Conference Proceedings O Standards Search O Basic O Advanced O CrossRef O Join IEEE O Establish IEEE Web Account O Access the IEEE Enterprise IEEE Member Digital Library IEEE Enterprise File Cabinet Your search matched 17 of 1121826 documents. A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order. Refine This Search: You may refine your search by editing the current search expression or entering new one in the text box. [edge or contour or line or ridge) <paragraph>(((inter) Search Check to search within this result set Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard 1 Computer-aided phase shift mask design with reduced complexity Yong Liu; Zakhor, A.; Zuniga, M.A.; Semiconductor Manufacturing, IEEE Transactions on , Volume: 9 , Issue: 2 , M 1996 Pages: 170 - 181 [Abstract] [PDF Full-Text (1380 KB)] IEEE JNL 2 Developing the GX graphics accelerator architecture Priem, C.R.; Micro, IEEE, Volume: 10 , Issue: 1 , Feb. 1990 Pages: 44 - 54 [Abstract] [PDF Full-Text (840 KB)] IEEE JNL 3 Stereo spatial super-resolution technique for multiple reentry vehicl Rago, C.; Landau, H.; Aerospace Conference, 2004. Proceedings. 2004 IEEE , Volume: 3 , 6-13 Marc 2004 Pages: 1841 Vol.3</paragraph>	Help FAQ Terms IEE	E Peer Review Quick Links >> Se.
A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order. A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order. Refine This Search: You may refine your search by editing the current search expression or entering new one in the text box. [edge or contour or line or ridge) <pre> Conference Proceedings </pre>	Welcome to IEEE Xplore®	
You may refine your search by editing the current search expression or entering new one in the text box. (edge or contour or line or ridge) < paragraph > (((inter Search Sea	O- What Can I Access?	A maximum of 500 results are displayed, 15 to a page, sorted by Relevance
Conference Proceedings Check to search within this result set	Tables of Contents	You may refine your search by editing the current search expression or enteri
Proceedings Standards Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard CNF	& Magazines	
Search JNL = Journal or Magazine CNF = Conference STD = Standard		Check to search within this result set
O- By Author O- Basic O- Advanced O- CrossRef Member Services O- Join IEEE O- Establish IEEE Web Account O- Access the IEEE Enterprise Digital Library D- Access the IEEE Enterprise File Cabinet Print Format 1 Computer-aided phase shift mask design with reduced complexity Yong Liu; Zakhor, A.; Zuniga, M.A.; Semiconductor Manufacturing, IEEE Transactions on , Volume: 9 , Issue: 2 , M 1996 Pages: 170 - 181 [Abstract] [PDF Full-Text (1380 KB)] IEEE JNL 2 Developing the GX graphics accelerator architecture Priem, C.R.; Micro, IEEE, Volume: 10 , Issue: 1 , Feb. 1990 Pages: 44 - 54 [Abstract] [PDF Full-Text (840 KB)] IEEE JNL 3 Stereo spatial super-resolution technique for multiple reentry vehicle Rago, C.; Landau, H.; Aerospace Conference, 2004. Proceedings. 2004 IEEE , Volume: 3 , 6-13 Marca 2004 Pages: 1841 Vol.3	O- Standards	
Computer-aided phase shift mask design with reduced complexity Yong Liu; Zakhor, A.; Zuniga, M.A.; Semiconductor Manufacturing, IEEE Transactions on , Volume: 9 , Issue: 2 , M 1996 Pages:170 - 181 [Abstract] [PDF Full-Text (1380 KB)] IEEE JNL Developing the GX graphics accelerator architecture Priem, C.R.; Micro, IEEE, Volume: 10 , Issue: 1 , Feb. 1990 Pages:44 - 54 [Abstract] [PDF Full-Text (840 KB)] IEEE JNL Access the IEEE Enterprise File Cabinet Access the IEEE Enterprise File Cabinet Access the IEEE Enterprise File Cabinet Access the IEEE Cabinet Acces	Search S *	JNL = Journal or Magazine CNF = Conference STD = Standard
O- Establish IEEE Web Account O- Access the IEEE Member Digital Library Comparison	O- Basic O- Advanced O- CrossRef	Yong Liu; Zakhor, A.; Zuniga, M.A.; Semiconductor Manufacturing, IEEE Transactions on , Volume: 9 , Issue: 2 , M 1996
Web Account	O- Join IEEE	[Abstract] [PDF Full-Text (1380 KB)] IEEE JNL
O- Access the IEEE Enterprise File Cabinet 3 Stereo spatial super-resolution technique for multiple reentry vehicle Rago, C.; Landau, H.; Aerospace Conference, 2004. Proceedings. 2004 IEEE, Volume: 3, 6-13 Marc 2004 Pages: 1841 Vol.3	Web Account - Access the IEEE Member	Priem, C.R.; Micro, IEEE, Volume: 10, Issue: 1, Feb. 1990
IEEE Enterprise File Cabinet 3 Stereo spatial super-resolution technique for multiple reentry vehicl Rago, C.; Landau, H.; Aerospace Conference, 2004. Proceedings. 2004 IEEE, Volume: 3, 6-13 Marc 2004 Pages: 1841 Vol.3	IEEE Enterprise	[Abstract] [PDF Full-Text (840 KB)] IEEE JNL
[Abstract] [PDF Full-Text (523 KB)] IEEE CNF	IEEE Enterprise File Cabinet	Rago, C.; Landau, H.; Aerospace Conference, 2004. Proceedings. 2004 IEEE, Volume: 3, 6-13 Marc 2004
		[Abstract] [PDF Full-Text (523 KB)] IEEE CNF

4 A new kind of impulse noise filter based on PCNN

Ma Yi-de; Shi Fei; Li Lian;

Neural Networks and Signal Processing, 2003. Proceedings of the 2003 International Conference on , Volume: 1 , 14-17 Dec. 2003 Pages:152 - 155 Vol.1

[Abstract] [PDF Full-Text (389 KB)] IEEE CNF

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE





Welcome United States Patent and Trademark Office



 Help	FAQ	Terms	IEEE	Peer	Review

Quick Links

Welcome	to	IEEE	Xpl	ore

- ()- Home
-)- What Can I Access?
- O- Log-out

Tables of Contents

- Journals & Magazines
- > Conference **Proceedings**
- O- Standards

Search

- O- By Author
- O- Basic
- O- Advanced
- CrossRef

Member Services

- ()- Join IEEE
- · Establish IEEE Web Account
- C Access the **IEEE Member** Digital Library

IEEE Enterprise

Access the **IEEE Enterprise** File Cabinet

Print Format

Your search matched 48 of 1121826 documents.

A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

(candidate<near>(edge or contour or line))<paragrai

Search

Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 An iterative procedure for removing random-valued impulse noise

Chan, R.H.; Chen Hu; Nikolova, M.;

Signal Processing Letters, IEEE , Volume: 11 , Issue: 12 , Dec. 2004 Pages:921 - 924

[Abstract] [PDF Full-Text (896 KB)] **IEEE JNL**

2 Binary-space-partitioned images for resolving image-based visibility

Fu, C.-W.; Tien-Tsin Wong; Wai-Shun Tong; Chi-Keung Tang; Hanson, A.J.; Visualization and Computer Graphics, IEEE Transactions on , Volume: 10 , Iss 1 , Jan-Feb 2004

Pages:58 - 71

[Abstract] [PDF Full-Text (2704 KB)]

3 Selective removal of impulse noise based on homogeneity level information

Gouchol Pok; Jyh-Charn Liu; Nair, A.S.;

Image Processing, IEEE Transactions on , Volume: 12 , Issue: 1 , Jan. 2003

Pages:85 - 92

[Abstract] [PDF Full-Text (1551 KB)] **IEEE JNL**

4 Localizing and segmenting text in images and videos

Lienhart, R.; Wernicke, A.;

Circuits and Systems for Video Technology, IEEE Transactions on , Volume:

12 , Issue: 4 , April 2002

Pages: 256 - 268

[Abstract] [PDF Full-Text (473 KB)] IEEE JNL

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S30	1	382/266.ccls. and (less near2((difference with (intensity or brightness or luminance))))with (contour or edge or line)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 06:09
S31	1	382/266.ccls. and ((less or greater or larger) near2((difference with (intensity or brightness or luminance))))with (contour or edge or line)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 06:24
S32	2	382/266,199.ccls. and ((less or greater or larger) near2((difference with (intensity or brightness or luminance))))with (contour or edge or line)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 06:26
S33	40	382/266,199.ccls. and (less or greater or larger) near2 (intensity or brightness or luminance)with (contour or edge or line)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR ·	ON	2005/01/27 06:27
S34	22	382/266,199.ccls. and (less or greater or larger) near2 (intensity or brightness or luminance)with (contour or edge or line)with pixel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 07:19
S35	30	382/266,199.ccls. and (less or greater or larger) near4 (intensity or brightness or luminance)with (contour or edge or line)with pixel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 10:08
S36	1.	"4783753".PN.	USPAT; USOCR	OR	OFF	2005/01/27 07:22
S37	32	382/266,199,218,224.ccls. and (less or greater or larger) near4 (intensity or brightness or luminance)with (contour or edge or line)with pixel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 10:35
S38	83	382/266,199,218,224.ccls. and (candidate with(contour or edge or line)with pixel)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 10:37
S39	24	382/266,199,218,224.ccls. and (candidate with(contour or edge or line)with pixel with (adjacent or surround\$4 or neighbor\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 10:41

S40	8	382/266,199,218,224.ccls. and (candidate with(contour or edge or line)with pixel with (adjacent))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/27 10:41
S41	2	("6408109" "6563538") PN:	US-PGPUB; USPAT; USOCR	OR	OFF	2005/01/27 10:46